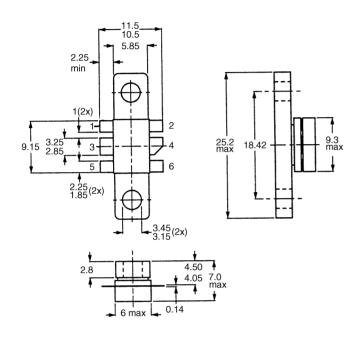


## **D1094UK**

## METAL GATE RF SILICON FET

#### **MECHANICAL DATA**



# **DMOS RF FET** 20W - 28V - 400MHzSINGLE ENDED **FEATURES**

- SIMPLIFIED AMPLIFIER DESIGN
- SUITABLE FOR BROAD BAND APPLICATIONS

**GOLD METALLISED** 

**MULTI-PURPOSE SILICON** 

- VERY LOW Crss
- SIMPLE BIAS CIRCUITS
- LOW NOISE
- HIGH GAIN 11 dB MINIMUM

### **SOT 171**

PIN 1 SOURCE PIN<sub>2</sub> SOURCE PIN 3 **GATE** PIN 4 DRAIN PIN 6 PIN 5 SOURCE SOURCE

## **APPLICATIONS**

 HE/VHE/UHE COMMUNICATIONS from 1 MHz to 1 GHz

## **ABSOLUTE MAXIMUM RATINGS** (T<sub>case</sub> = 25°C unless otherwise stated)

$P_{D}$	Power Dissipation	50W
$BV_{DSS}$	Drain – Source Breakdown Voltage	65V
$BV_GSS$	Gate – Source Breakdown Voltage	±20V
I <sub>D(sat)</sub>	Drain Current *	6A
T <sub>stg</sub>	Storage Temperature	–65 to 150°C
Tj	Maximum Operating Junction Temperature	200°C

E-mail: sales@semelab.co.uk Website http://www.semelab.co.uk



## **D1094UK**

## **ELECTRICAL CHARACTERISTICS** (T<sub>case</sub> = 25°C unless otherwise stated)

Parameter		Test Conditions		Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source	V <sub>GS</sub> = 0	I <sub>D</sub> = 10mA	65			V
	Breakdown Voltage			03			
I <sub>DSS</sub>	Zero Gate Voltage	V <sub>DS</sub> = 28V	V V <sub>GS</sub> = 0			6	mΛ
	Drain Current					0	mA
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> = 20V	$V_{DS} = 0$			6	μΑ
V <sub>GS(th)</sub>	Gate Threshold Voltage *	I <sub>D</sub> = 10mA	$V_{DS} = V_{GS}$	1		7	V
9 <sub>fs</sub>	Forward Transconductance *	V <sub>DS</sub> = 10V	I <sub>D</sub> = 0.6A	1.08			S
G <sub>PS</sub>	Common Source Power Gain	P <sub>O</sub> = 20W		11			dB
η	Drain Efficiency	V <sub>DS</sub> = 28V	$I_{DQ} = 0.6A$	50			%
VSWR	Load Mismatch Tolerance	f = 400MH	Z	20:1			_
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 0$	$V_{GS} = -5V$ $f = 1MHz$			72	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 28V	$V_{GS} = 0$ $f = 1MHz$			36	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	V <sub>DS</sub> = 28V	$V_{GS} = 0$ $f = 1MHz$			3	pF

<sup>\*</sup> Pulse Test: Pulse Duration = 300  $\mu s$ , Duty Cycle  $\leq 2\%$ 

## **HAZARDOUS MATERIAL WARNING**

The ceramic portion of the device between leads and metal flange is beryllium oxide. Beryllium oxide dust is highly toxic and care must be taken during handling and mounting to avoid damage to this area.

#### THESE DEVICES MUST NEVER BE THROWN AWAY WITH GENERAL INDUSTRIAL OR DOMESTIC WASTE.

#### THERMAL DATA

R <sub>THj-case</sub>	Thermal Resistance Junction – Case	Max.3.5°C / W
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